SPB03N60C3



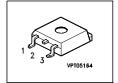
Cool MOS™ Power Transistor

Feature

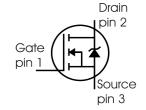
- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- High peak current capability
- Improved transconductance
- Qualified according to JEDEC⁰⁾ for target applications

V _{DS} @ T _{jmax}	650	٧
R _{DS(on)}	1.4	Ω
/ _D	3.2	Α

PG-TO263



Туре	Package	Ordering Code	Marking
SPB03N60C3	PG-TO263	Q67040-S4391	03N60C3



Maximum Ratings

Parameter	Symbol	Value	Unit
		SPB	
Continuous drain current	I _D		А
$T_{\rm C}$ = 25 °C		3.2	
T _C = 100 °C		2	
Pulsed drain current, t_p limited by T_{jmax}	I _{D puls}	9.6	Α
Avalanche energy, single pulse	E _{AS}	100	mJ
I _D =2.4A, V _{DD} =50V			
Avalanche energy, repetitive t_{AR} limited by T_{jmax}^2)	E _{AR}	0.2	
I _D =3.2A, V _{DD} =50V			
Avalanche current, repetitive t_{AR} limited by T_{jmax}	I _{AR}	3.2	А
Gate source voltage static	V _{GS}	±20	V
Gate source voltage AC (f >1Hz)	V_{GS}	±30	
Power dissipation, $T_C = 25^{\circ}C$	P _{tot}	38	W
Operating and storage temperature	T _i , T _{stg}	-55+150	°C
Reverse diode dv/dt ⁷⁾	dv/dt	15	V/ns



Maximum Ratings

Parameter	Symbol	Value	Unit
Drain Source voltage slope	d <i>v</i> /d <i>t</i>	50	V/ns
$V_{\rm DS}$ = 480 V, $I_{\rm D}$ = 3.2 A, $T_{\rm j}$ = 125 °C			

Thermal Characteristics

Parameter	Symbol	nbol Values		Unit	
		min.	typ.	max.	
Thermal resistance, junction - case	R _{thJC}	-	-	3.3	K/W
Thermal resistance, junction - case, FullPAK	R _{thJC_FP}	-	-	4.1	
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	62	
Thermal resistance, junction - ambient, FullPAK	R _{thJA_FP}	-	-	80	
SMD version, device on PCB:	R _{thJA}				
@ min. footprint		-	-	62	
@ 6 cm ² cooling area ³⁾		-	35	-	
Soldering temperature, reflow soldering, MSL1	T_{sold}	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s					

Electrical Characteristics, at T_i =25°C unless otherwise specified

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =0.25mA	600	-	-	V
Drain-Source avalanche breakdown voltage	V _{(BR)DS}	V _{GS} =0V, I _D =3.2A	-	700	-	
Gate threshold voltage	V _{GS(th)}	I _D =135μA, V _{GS} =V _{DS}	2.1	3	3.9	
Zero gate voltage drain current	I _{DSS}	V _{DS} =600V, V _{GS} =0V,				μΑ
		<i>T</i> _j =25°C	-	0.5	1	
		<i>T</i> _j =150°C	-	-	70	
Gate-source leakage current	I_{GSS}	V _{GS} =30V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10V, I _D =2A				Ω
	, ,	<i>T</i> _j =25°C	-	1.26	1.4	
		<i>T</i> _j =150°C	-	3.8	-	
Gate input resistance	R_{G}	f=1MHz, open drain	-	10	-	



Electrical Characteristics

Parameter	Symbol	Conditions	ons Values			Unit
			min.	typ.	max.	
Transconductance	<i>g</i> fs	$V_{DS} \ge 2*I_{D}*R_{DS(on)max}$	-	3.4	-	S
		I _D =2A				
Input capacitance	C _{iss}	V _{GS} =0V, V _{DS} =25V,	-	400	-	pF
Output capacitance	Coss	f=1MHz	-	150	-	
Reverse transfer capacitance	C _{rss}		-	5	-	
Effective output capacitance,5)	C _{o(er)}	V _{GS} =0V,	-	12	-	
energy related		V _{DS} =0V to 480V				
Effective output capacitance,6)	C _{o(tr)}		-	26	-	
time related	, ,					
Turn-on delay time	t _{d(on)}	V _{DD} =350V, V _{GS} =0/10V,	-	7	-	ns
Rise time	t _r	I _D =3.2A,	-	3	-	
Turn-off delay time	t _{d(off)}	R_{G} =20 Ω	-	64	100	
Fall time	<i>t</i> _f		-	12	20	

Gate Charge Characteristics

Gate to source charge	Q _{gs}	V _{DD} =420V, I _D =3.2A	-	2	-	nC
Gate to drain charge	Q_{gd}		-	6	ı	
Gate charge total	Q_g	V _{DD} =420V, I _D =3.2A,	-	13	17	
		V _{GS} =0 to 10V				
Gate plateau voltage	V _(plateau)	V _{DD} =420V, I _D =3.2A	-	5.5	-	V

⁰J-STD20 and JESD22

¹Limited only by maximum temperature

²Repetitve avalanche causes additional power losses that can be calculated as $P_{AV} = E_{AR} * f$.

 $^{^3}$ Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical without blown air.

 $^{^4}C_{
m o(er)}$ is a fixed capacitance that gives the same stored energy as $C_{
m oss}$ while $V_{
m DS}$ is rising from 0 to 80% $V_{
m DSS}$.

 $^{^5}C_{\mathrm{O(tr)}}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 80% V_{DSS} .

 $^{^{6}}$ I_{SD}<=I_D, di/dt<=400A/us, V_{DClink}=400V, V_{peak}<V_{BR, DSS}, T_j<T_{j,max}. Identical low-side and high-side switch.

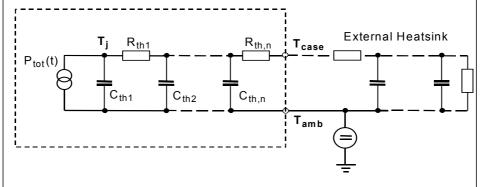


Electrical Characteristics

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Inverse diode continuous	IS	<i>T</i> _C =25°C	-	-	3.2	Α
forward current						
Inverse diode direct current,	I _{SM}		-	-	9.6	
pulsed						
Inverse diode forward voltage	V_{SD}	V _{GS} =0V, I _F =I _S	-	1	1.2	V
Reverse recovery time	t_{rr}	V_{R} =420V, I_{F} = I_{S} ,	-	250	400	ns
Reverse recovery charge	Q _{rr}	d <i>i_F</i> /d <i>t</i> =100A/μs	-	1.8	-	μC
Peak reverse recovery current	/ _{rrm}		-	15	-	Α
Peak rate of fall of reverse	di _{rr} /dt	<i>T</i> _j =25°C	-	-	-	A/µs
recovery current						

Typical Transient Thermal Characteristics

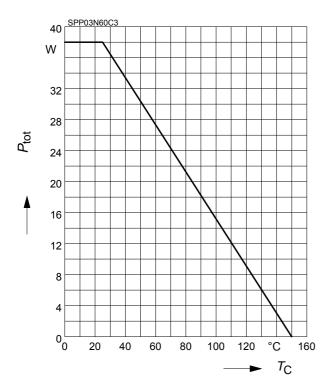
Symbol	Va	lue	Unit	Symbol	Va	lue	Unit
	SPB				SPB		
R _{th1}	0.054		K/W	C _{th1}	0.00005232		Ws/K
R _{th2}	0.103			C _{th2}	0.0002034		
R _{th3}	0.178			C _{th3}	0.0002963		
R _{th4}	0.757			C _{th4}	0.0009103		
R _{th5}	0.682			C _{th5}	0.002084		
R _{th6}	0.202			C _{th6}	0.024		





1 Power dissipation

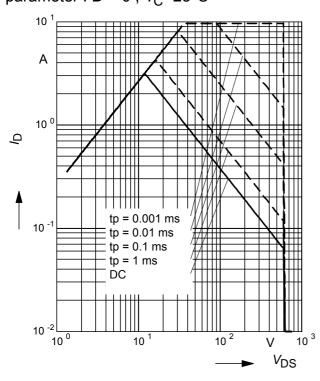
$$P_{\text{tot}} = f(T_{\text{C}})$$



3 Safe operating area

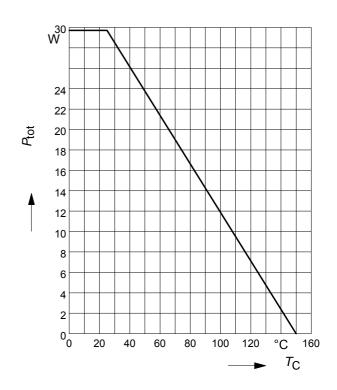
$$I_{D} = f(V_{DS})$$

parameter : D = 0 , $T_C = 25$ °C



2 Power dissipation FullPAK

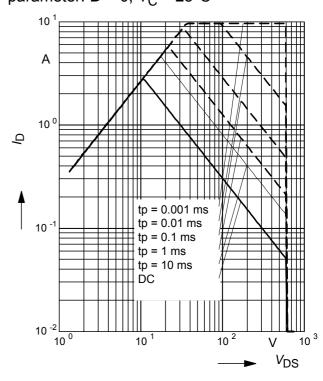
$$P_{\text{tot}} = f(T_{\text{C}})$$



4 Safe operating area FullPAK

$$I_{D} = f(V_{DS})$$

parameter: D = 0, $T_C = 25$ °C

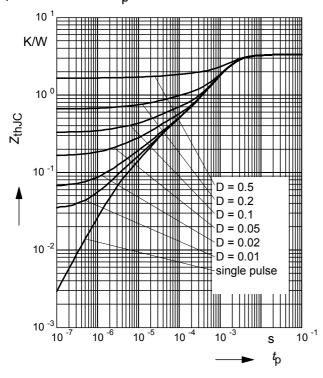




5 Transient thermal impedance

$$Z_{\mathsf{thJC}} = f\left(t_{\mathsf{p}}\right)$$

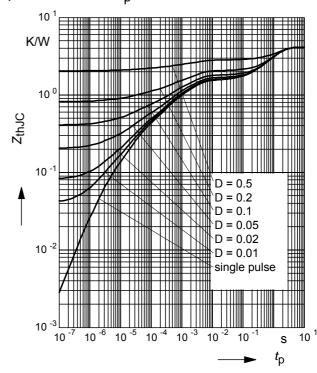
parameter: $D = t_D/T$



6 Transient thermal impedance FullPAK

$$Z_{\mathsf{thJC}} = f\left(t_{\mathsf{p}}\right)$$

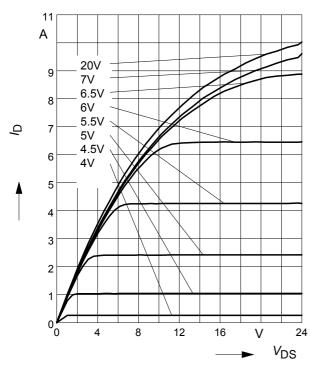
parameter: $D = t_D/t$



7 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{i}=25^{\circ}C$

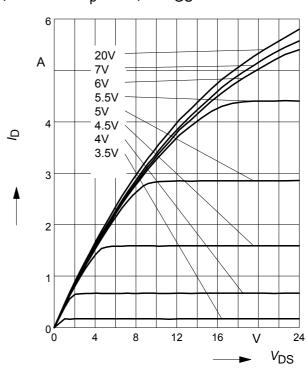
parameter: t_p = 10 μ s, V_{GS}



8 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{j}=150^{\circ}C$

parameter: t_p = 10 μ s, V_{GS}

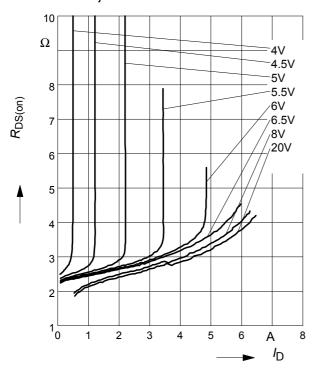




9 Typ. drain-source on resistance

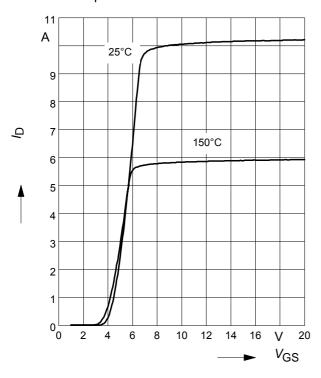
 $R_{DS(on)} = f(I_D)$

parameter: T_i =150°C, V_{GS}



11 Typ. transfer characteristics

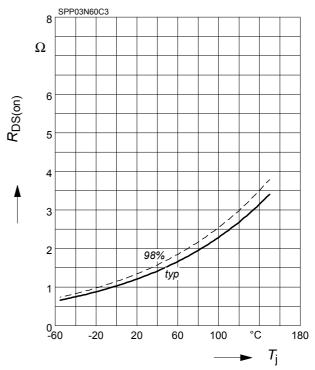
 $I_{\rm D}$ = f ($V_{\rm GS}$); $V_{\rm DS}$ \geq 2 x $I_{\rm D}$ x $R_{\rm DS(on)max}$ parameter: $t_{\rm p}$ = 10 μ s



10 Drain-source on-state resistance

 $R_{\text{DS(on)}} = f(T_{j})$

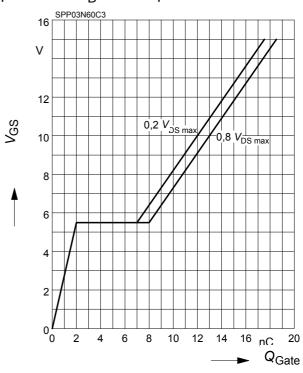
parameter : I_D = 2 A, V_{GS} = 10 V



12 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$

parameter: I_D = 3.2 A pulsed

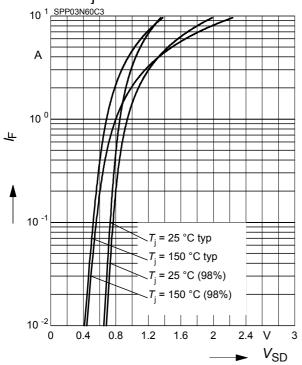




13 Forward characteristics of body diode

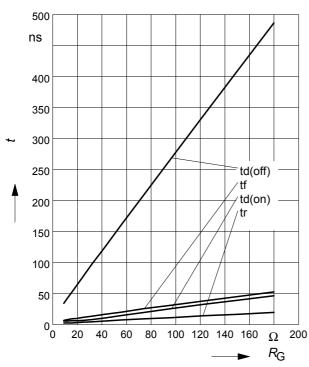
 $I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$

parameter: T_i , $tp = 10 \mu s$



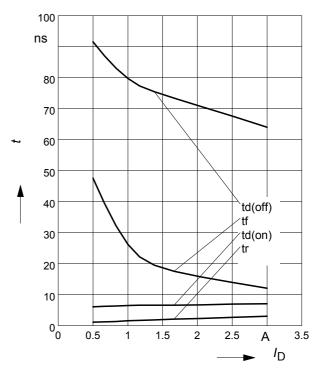
15 Typ. switching time

 $t = f(R_G)$, inductive load, T_j =125°C par.: V_{DS} =380V, V_{GS} =0/+13V, I_D =3.2 A



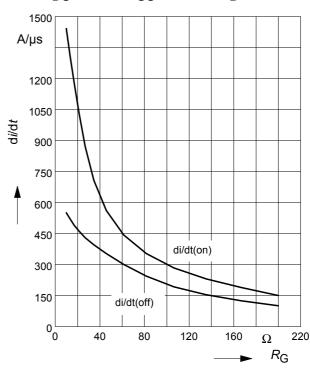
14 Typ. switching time

 $t = f(I_{\rm D})$, inductive load, $T_{\rm j}$ =125°C par.: $V_{\rm DS}$ =380V, $V_{\rm GS}$ =0/+13V, $R_{\rm G}$ =20 Ω



16 Typ. drain current slope

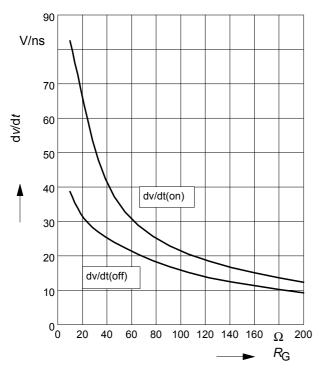
 $di/dt = f(R_G)$, inductive load, $T_j = 125$ °C par.: $V_{DS}=380$ V, $V_{GS}=0/+13$ V, $I_D=3.2$ A





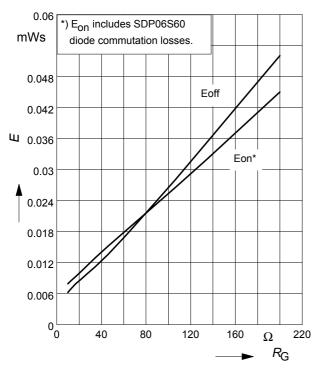
17 Typ. drain source voltage slope

 $dv/dt = f(R_G)$, inductive load, $T_j = 125$ °C par.: V_{DS} =380V, V_{GS} =0/+13V, I_D =3.2A



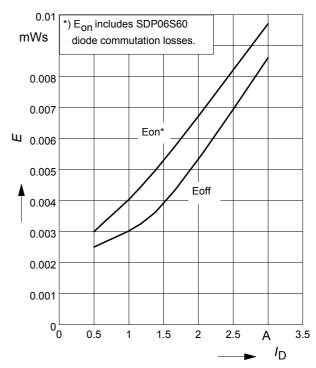
19 Typ. switching losses

 $E = f(R_G)$, inductive load, T_j =125°C par.: V_{DS} =380V, V_{GS} =0/+13V, I_D =3.2A



18 Typ. switching losses

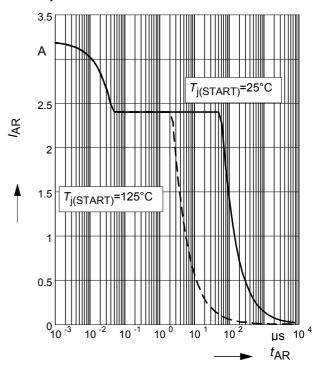
 $E = f(I_{\rm D})$, inductive load, $T_{\rm j}$ =125°C par.: $V_{\rm DS}$ =380V, $V_{\rm GS}$ =0/+13V, $R_{\rm G}$ =20 Ω



20 Avalanche SOA

 $I_{AR} = f(t_{AR})$

par.: $T_j \le 150 \,^{\circ}\text{C}$



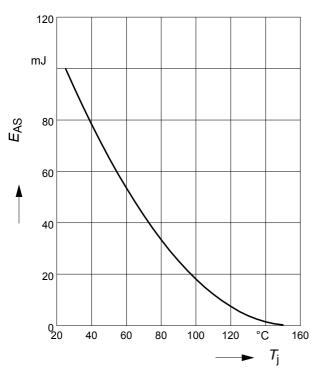
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21 Avalanche energy

$$E_{AS} = f(T_i)$$

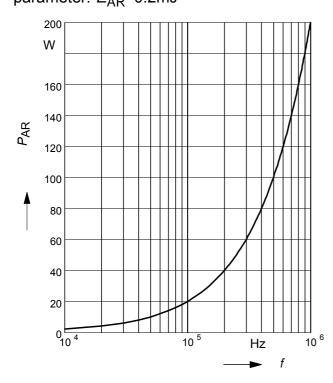
par.:
$$I_D = 2.4 \text{ A}, V_{DD} = 50 \text{ V}$$



23 Avalanche power losses

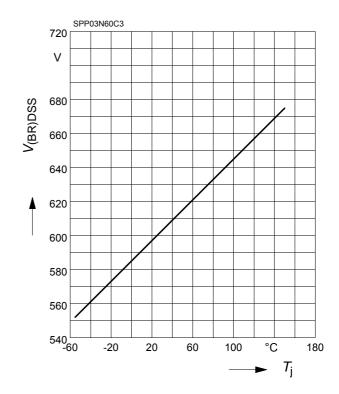
$$P_{AR} = f(f)$$

parameter: E_{AR} =0.2mJ



22 Drain-source breakdown voltage

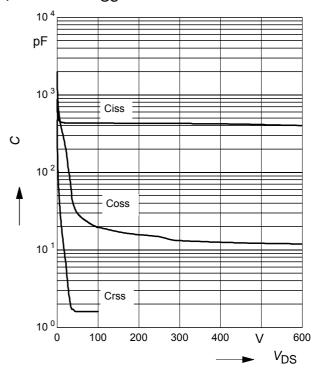
$$V_{(\mathsf{BR})\mathsf{DSS}} = f(T_{\mathsf{j}})$$



24 Typ. capacitances

$$C = f(V_{DS})$$

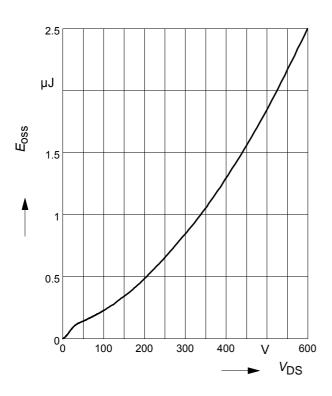
parameter: V_{GS}=0V, f=1 MHz



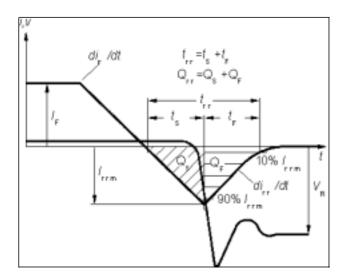


25 Typ. $C_{\rm OSS}$ stored energy

$$E_{\rm oss} = f(V_{\rm DS})$$

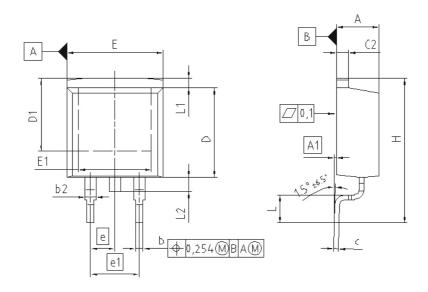


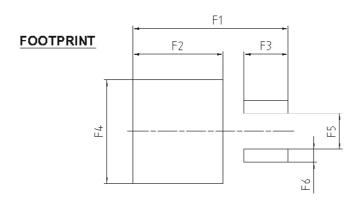
Definition of diodes switching characteristics



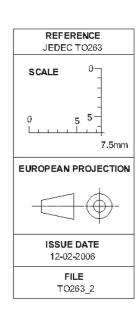


PG-TO263-3-2/ PG-TO263-3-5/ PG-TO263-3-22





DIM	MILLIM	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.300	4.572	0.169	0.180	
A1	0.000	0.254	0.000	0.010	
b	0.650	0.850	0.026	0.033	
b2	0.950	1.321	0.037	0.052	
C	0.330	0.650	0.013	0.026	
c2	0.170	1.400	0.046	0.055	
D	8.509	9.450	0.335	0.372	
D1	7.100	-	0.280	-	
E	9.800	10.312	0.386	0.406	
E1	6.500	-	0.256		
e	2.5	540	0.1	100	
e1	5.0	080	0.2	200	
N		2	3	2	
Н	14.605	15.875	0.575	0.625	
L	2.200	3.000	0.087	0.118	
L1	-	1.600	-	0.063	
L2	1.000	1.778	0.039	0.070	
F1	16.050	16.250	0.632	0.640	
F2	9.300	9.500	0.366	0.374	
F3	4.500	4.700	0.177	0.185	
F4	10.700	10.900	0.421	0.429	
F5	3.630	3.830	0.143	0.151	
F6	1.100	1.300	0.043	0.051	





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